


<b>Search Notes</b>  	<b>Application/Control No.</b>  10717607	<b>Applicant(s)/Patent Under Reexamination</b>  KIM ET AL.
	<b>Examiner</b>  Keefer, Michael E	<b>Art Unit</b>  2154

SEARCHED			
Class	Subclass	Date	Examiner
709	227 (updated 6/7/200)8	7/13/2007	MEK

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Search	7/13/2007	MEK
Consulted Examiner Hassan Phillips	7/12/2007	MEK
Consulted Examiner Dustin Nguyen	7/12/2007	MEK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner